PCN Number: 2			20230919000.1				PCN Date:		te:	September 19, 2023	
Title:	Qualification of RFAB as an additional Fab site option for select HPA07 devices										
Customer	Contact:	Chan	ge Ma	Management team Dept			t: Quality Ser			rvices	
Proposed 1 st Ship Date: Dec 1			c 19, 2023			Sample requests accepted until:			October 19, 2023*		
*Sample requests received after October 19, 2023 will not be supported. Change Type: Assembly Site Dec 19, 2023 accepted until: Wafer Bump Material											
Change Ty	pe:										
Assem	bly Site				Design				Wafe	r Bump Material	
Assembly Process				Data Sheet				Wafe	r Bump Process		
Assembly Materials				Part number o	Part number change			Wafer Fab Site			
■ Mechanical Specification				Test Site			\boxtimes	Wafer Fab Material			
☐ Packing/Shipping/Labeling					Test Process				Wafer Fab Process		
					PCN Detai	ls					
Description	n of Chang	e:									

Texas Instruments is pleased to announce the addition of RFAB as an additional Wafer Fab site option for the products listed in the "Product Affected" section of this document.

С	urrent Fab Site	9	New Fab Site				
Current Fab Process Site		Wafer Diameter	New Fab Site	Process	Wafer Diameter		
DP1DM5	HPA 07	200mm	RFAB	HPA07	300mm		

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City		
DP1DM5	DM5	USA	Dallas		
RFAB	RFB	USA	Richardson		

Sample product shipping label (not actual product label)



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACCURA

Product Affected:

ADS131E04IPAG	ADS131E06IPAG	ADS131E08IPAG
ADS131E04IPAGR	ADS131E06IPAGR	ADS131E08IPAGR

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: ADS131E08IPAGR	QBS Process Reference: CD3232A1YFFR	QBS Process Reference: CD3232A1YFFR	QBS Process Reference: AMC7836IPAP	QBS Process Reference: INA231AIYFDR	QBS Process Reference: INA231BIYFDR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	-	-	-
тс	A4	Temperature Cycle	-55C/125C	700 Cycles	-	3/231/0	3/231/0	-	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	3/231/0	-	1/77/0	2/154/0
HTOL	B1	Life Test	140C	480 Hours	-	1/77/0	2/154/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	1/77/0	2/154/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	1/1000/0	2/2000/0	-	1/1000/0	2/2000/0
ESD	E2	ESD CDM	-	1000 Volts	-	-	-	1/3/0	-	-
ESD	E2	ESD CDM		200 Volts	-	-	3/9/0	-	-	-
ESD	E2	ESD CDM	-	500 Volts	1/3/0	-	-	-	-	2/6/0
ESD	E2	ESD CDM	-	350 Volts	-	-	-	-	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	3/9/0	3/9/0	-	-	2/6/0
ESD	E2	ESD HBM	-	2500 Volts	-	-	-	1/3/0	-	-
ESD	E2	ESD HBM	-	1500 Volts	-	-	-	-	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	3/9/0	3/9/0	1/3/0	1/6/0	2/12/0
CHAR	E 5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	2/60/0
FTY	E6	Final Test Yield	-	-	1/Pass	-	-	-	-	-

- QBS: Qual By Similarity
- Qual Device ADS131E08IPAGR is qualified at MSL3 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-NPD-2211-033

For questions regarding this notice, e-mails can be sent to Change Management team or your local Field Sales Representative.

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